Substitute for form 1449A/PTO Complete if Known INFORMATION DISCLOSURE **Application Number** 08/902133 STATEMENT BY APPLICANT July 29, 1997 Filing Date Forbes, Leonard **First Named Inventor Group Art Unit** 2815 APR 0 3 2003 **Examiner Name** Eckert II, George Attorney Docket No: 303.356US1 Sheet 1 of 2

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